

M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT)DYNAMIC RAM

DESCRIPTION

This is a family of 4194304-word by 1-bit dynamic RAMS, fabricated with the high performance CMOS process, and is ideal for large-capacity memory systems where high speed, low power dissipation, and low costs are essential. The use of quadruple-layer polysilicon process combined with silicide technology and a single-transistor dynamic storage stacked capacitor cell provide high circuit density at reduced costs. Multiplexed address inputs permit both a reduction in pins and an increase in system densities.

The M5M44100ATP, RT are packaged in a 26-pin very thin and small outline package which is a high reliability and high density surface mount device. Two types of devices are available. M5M44100ATP(normal lead bend type package), M5M44100ART(reverse lead bend type package). Using both types of devices, it becomes very easy to design a printed circuit board.

FEATURES

Type name	RAS access time (max. ns)	CAS access time (max. ns)	Address access time (max. ns)	Cycle time (min. ns)	Power dissipation (typ.mW)
M5M44100AXX-6	60	15	30	120	400
M5M44100AXX-7	70	20	35	140	350
M5M44100AXX-8	80	20	40	160	300
M5M44100AXX-10	100	25	50	190	250

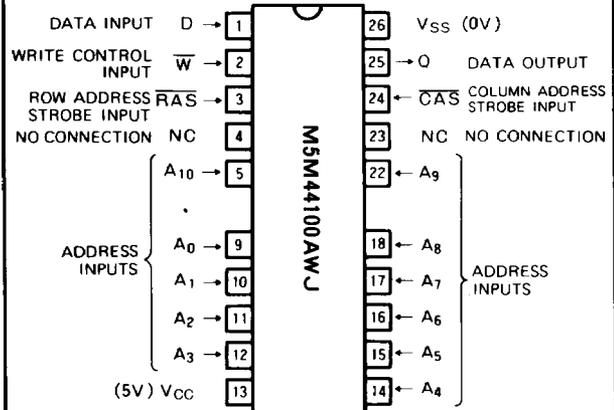
XX=WJ, J, L, TP, RT

- Standard 26 pin SOJ, 20 pin ZIP, 26 pin TSOP
- Single 5V ± 10% supply
- Low stand-by power dissipation
5.5mW (Max) CMOS Input level
- Low operating power dissipation
M5M44100Axx-6 550.0mW (Max)
M5M44100Axx-7 467.5mW (Max)
M5M44100Axx-8 412.5mW (Max)
M5M44100Axx-10 357.5mW (Max)
- Fast-page mode (2048-bit random access), Read-modify-write, RAS-only refresh CAS before RAS refresh, Hidden refresh capabilities
- Early-write operation gives common I/O capability
- All inputs, output TTL compatible and low capacitance
- 1024 refresh cycles every 16.4ms (A₀ ~ A₉)
- 16-bit parallel test mode capability

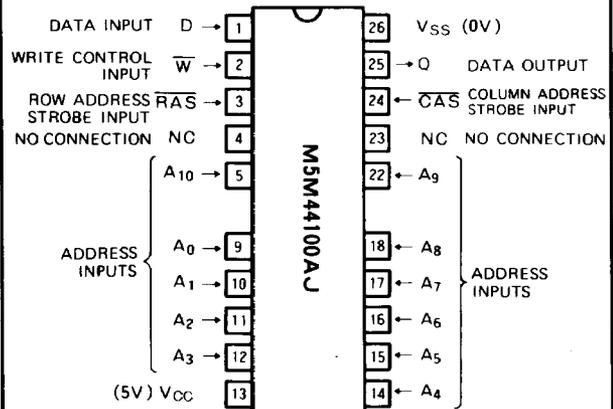
APPLICATION

Main memory unit for computers, Microcomputer memory, Refresh memory for CRT

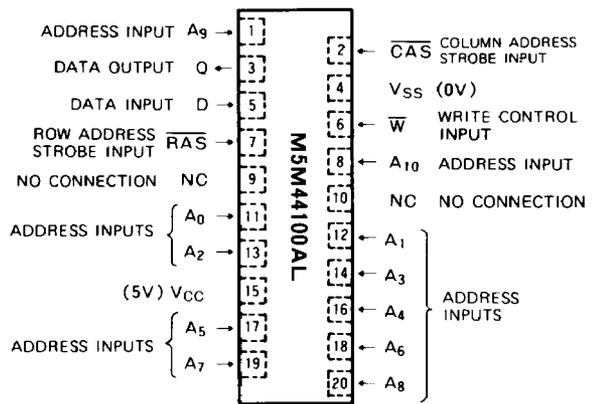
PIN CONFIGURATION (TOP VIEW)



Outline 26P0Z (350 mil SOJ)



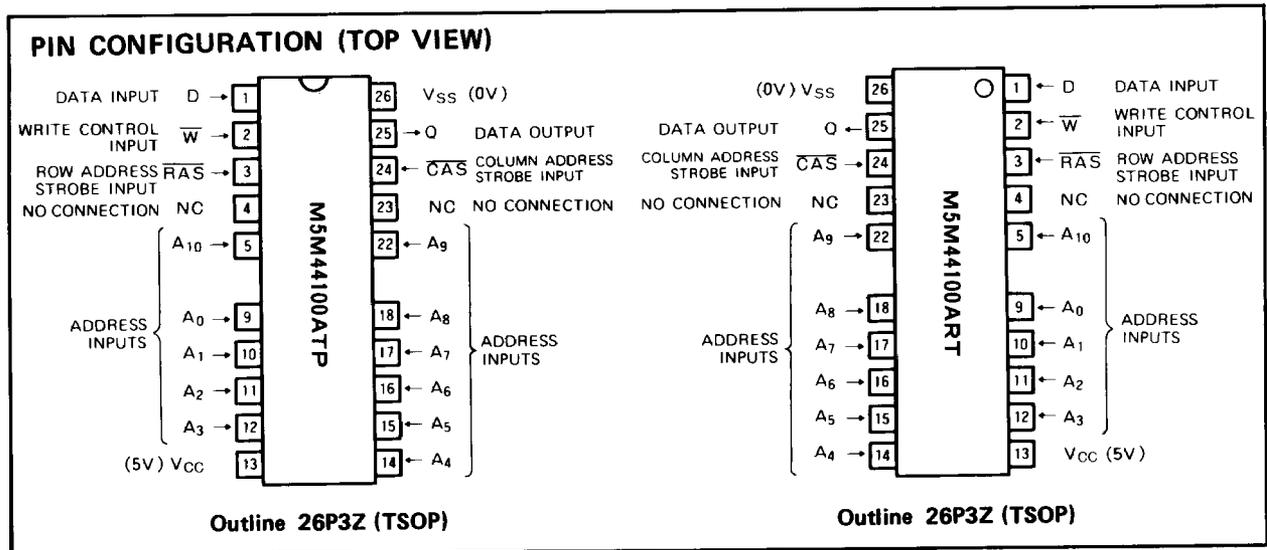
Outline 26P0J (300 mil SOJ)



Outline 20P5L-B (ZIP)

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FUNCTION

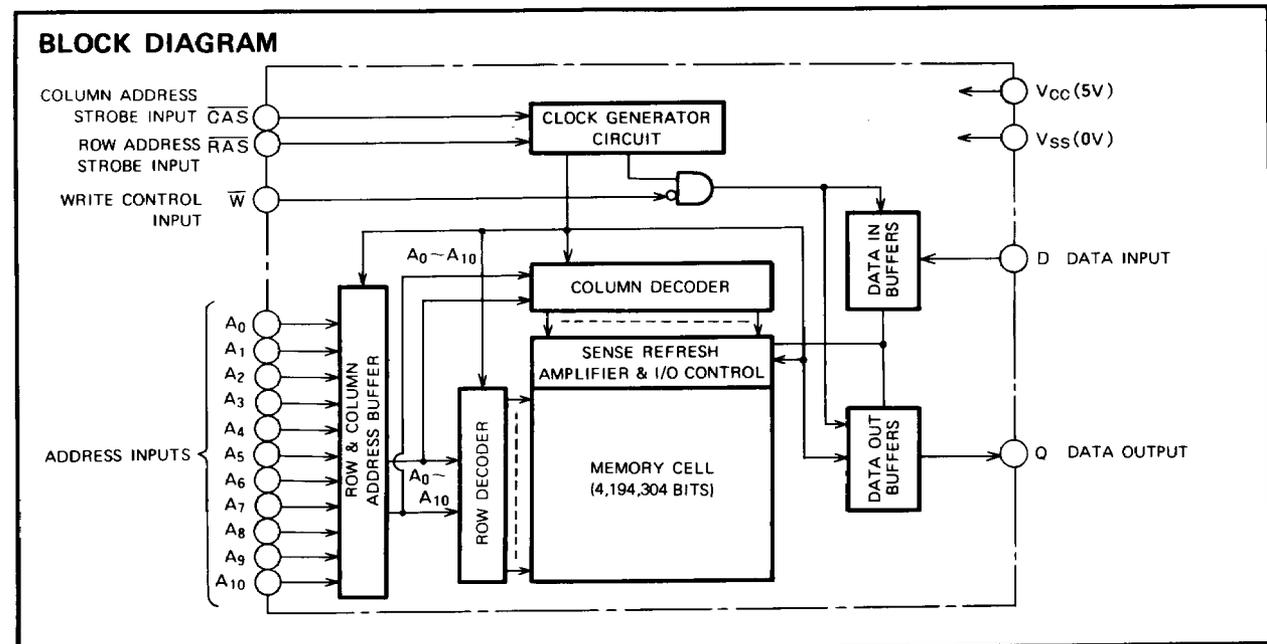
The M5M44100AWJ, J, L, TP, RT provide, in addition to normal read, write, and read-modify-write operations,

a number of other functions, e.g., fast page mode, \overline{RAS} -only refresh, and delayed-write. The input conditions for each are shown in Table 1.

Table 1 Input conditions for each mode

Operation	Inputs						Output	Refresh	Remark
	\overline{RAS}	\overline{CAS}	\overline{W}	D	Row address	Column address	Q		
Read	ACT	ACT	NAC	DNC	APD	APD	VLD	YES	Fast page mode identical
Write (Early write)	ACT	ACT	ACT	VLD	APD	APD	OPN	YES	
Write (Delayed write)	ACT	ACT	ACT	VLD	APD	APD	IVD	YES	
Read-modify-write	ACT	ACT	ACT	VLD	APD	APD	VLD	YES	
\overline{RAS} -only refresh	ACT	NAC	DNC	DNC	APD	DNC	OPN	YES	
Hidden refresh	ACT	ACT	DNC	DNC	DNC	DNC	VLD	YES	
\overline{CAS} before \overline{RAS} refresh	ACT	ACT	NAC	DNC	DNC	DNC	OPN	YES	
Stand-by	NAC	DNC	DNC	DNC	DNC	DNC	OPN	NO	

Note: ACT: active, NAC: nonactive, DNC: don't care, VLD: valid, IVD: invalid, APD: applied, OPN: open



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ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Unit
V _{CC}	Supply voltage	With respect to V _{SS}	-1 ~ 7	V
V _I	Input voltage		-1 ~ 7	V
V _O	Output voltage		-1 ~ 7	V
I _O	Output current		50	mA
P _d	Power dissipation	T _a = 25°C	1000	mW
T _{opr}	Operating temperature		0 ~ 70	°C
T _{stg}	Storage temperature		-65 ~ 150	°C

RECOMMENDED OPERATING CONDITIONS (T_a = 0 ~ 70°C, unless otherwise noted) (Note 1)

Symbol	Parameter	Limits			Unit
		Min	Nom	Max	
V _{CC}	Supply voltage	4.5	5	5.5	V
V _{SS}	Supply voltage	0	0	0	V
V _{IH}	High-level input voltage, all inputs	2.4		6.5	V
V _{IL}	Low-level input voltage, all inputs	-2.0		0.8	V

Note 1: All voltage values are with respect to V_{SS}.

ELECTRICAL CHARACTERISTICS (T_a = 0 ~ 70°C, V_{CC} = 5V ± 10%, V_{SS} = 0V, unless otherwise noted) (Note 2)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
V _{OH}	High-level output voltage	I _{OH} = -5mA	2.4		V _{CC}	V
V _{OL}	Low-level output voltage	I _{OL} = 4.2mA	0		0.4	V
I _{OZ}	Off-state output current	Q floating 0V ≤ V _{OUT} ≤ 5.5V	-10		10	μA
I _I	Input current	0V ≤ V _{IN} ≤ 6.5, Other input pins = 0V	-10		10	μA
I _{CC1(AV)}	Average supply current from V _{CC} operating (Note 3, 4)	M5M44100A-6 M5M44100A-7 M5M44100A-8 M5M44100A-10 R _{AS} , C _{AS} cycling t _{RC} = t _{wc} = min. output open			100	mA
					85	
					75	
					65	
I _{CC2}	Supply current from V _{CC} , stand-by (Note 5)	R _{AS} = C _{AS} = V _{IH} , output open			2	mA
		R _{AS} = C _{AS} ≥ V _{CC} - 0.5, output open			1	
I _{CC3(AV)}	Average supply current from V _{CC} refreshing (Note 3)	M5M44100A-6 M5M44100A-7 M5M44100A-8 M5M44100A-10 R _{AS} cycling, C _{AS} = V _{IH} t _{RC} = min. output open			100	mA
					85	
					75	
					65	
I _{CC4(AV)}	Average supply current from V _{CC} Fast-Page-Mode (Note 3, 4)	M5M44100A-6 M5M44100A-7 M5M44100A-8 M5M44100A-10 R _{AS} = V _{IL} , C _{AS} cycling t _{PC} = min. output open			100	mA
					85	
					75	
					65	
I _{CC6(AV)}	Average supply current from V _{CC} C _{AS} before R _{AS} refresh mode (Note 3)	M5M44100A-6 M5M44100A-7 M5M44100A-8 M5M44100A-10 C _{AS} before R _{AS} refresh cycling t _{RC} = min. output open			85	mA
					75	
					65	
					55	
					55	

Note 2: Current flowing into an IC is positive, out is negative.

3: I_{CC1(AV)}, I_{CC3(AV)}, I_{CC4(AV)} and I_{CC6(AV)} are dependent on cycle rate. Maximum current is measured at the fastest cycle rate.

4: I_{CC1(AV)} and I_{CC4(AV)} are dependent on output loading. Specified values are obtained with the output open.

CAPACITANCE (T_a = 0 ~ 70°C, V_{CC} = 5V ± 10%, V_{SS} = 0V, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
C _{I(A)}	Input capacitance, address inputs	V _I = V _{SS} f = 1MHz V _I = 25mVrms			5	pF
			M5M44100AWJ, J, TP, RT			
M5M44100AL				5		
C _{I(D)}	Input capacitance, data input				7	pF
C _{I(W)}	Input capacitance, write control input				7	pF
C _{I(R_{AS})}	Input capacitance, R _{AS} input				7	pF
C _{I(C_{AS})}	Input capacitance, C _{AS} input				7	pF
C _O	Output capacitance	V _O = V _{SS} , f = 1MHz, V _I = 25mVrms			7	pF

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SWITCHING CHARACTERISTICS ($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$, unless otherwise noted) (Notes 5, 12, 13)

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{CAC}	Access time from \overline{CAS} (Note 6, 7)		15		20		20		25	ns
t_{RAC}	Access time from \overline{RAS} (Note 6, 8)		60		70		80		100	ns
t_{AA}	Column address access time (Note 6, 9)		30		35		40		50	ns
t_{CPA}	Access time from \overline{CAS} precharge (Note 6, 10)		35		40		45		55	ns
t_{CLZ}	Output low impedance time from \overline{CAS} low (Note 6)	5		5		5		5		ns
t_{OFF}	Output disable time after \overline{CAS} high (Note 11)	0	15	0	20	0	20	0	25	ns

- Note 5: An initial pause of 500 μ s is required after power-up followed by a minimum of eight initialization cycles (any combination of cycles containing a \overline{RAS} clock such as \overline{RAS} -Only refresh).
 Note the \overline{RAS} may be cycled during the initial pause. And any 8 \overline{RAS} or $\overline{RAS}/\overline{CAS}$ cycles are required after prolonged periods (greater than 16.4 ms) of \overline{RAS} inactivity before proper device operation is achieved.
- 6: Measured with a load circuit equivalent to 2TTL loads and 100pF.
 7: Assumes that $t_{RCD} \geq t_{RCD(max)}$ and $t_{ASC} \geq t_{ASC(max)}$.
 8: Assumes that $t_{RCD} \leq t_{RCD(max)}$ and $t_{RAD} \leq t_{RAD(max)}$. If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} will increase by amount that t_{RCD} or t_{RAD} exceeds the value shown.
 9: Assumes that $t_{RAD} \geq t_{RAD(max)}$ and $t_{ASC} \leq t_{ASC(max)}$.
 10: Assumes that $t_{CP} \leq t_{CP(max)}$ and $t_{ASC} \geq t_{ASC(max)}$.
 11: $t_{OFF(max)}$ defines the time at which the output achieves the high impedance state ($I_{OUT} \leq \pm 10\mu\text{A}$) and is not reference to $V_{OH(min)}$ or $V_{OL(max)}$.

TIMING REQUIREMENTS (For Read, Write, Read-Modify-Write, Refresh, and Fast-Page Mode Cycles)

($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$, unless otherwise noted) (Notes 12, 13)

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{REF}	Refresh cycle time		16.4		16.4		16.4		16.4	ms
t_{RP}	\overline{RAS} high pulse width	50		60		70		80		ns
t_{RCD}	Delay time, \overline{RAS} low to \overline{CAS} low (Note 14)	20	45	20	50	20	60	25	75	ns
t_{CRP}	Delay time, \overline{CAS} high to \overline{RAS} low	10		10		10		10		ns
t_{RPC}	Delay time, \overline{RAS} high to \overline{CAS} low	0		0		0		0		ns
t_{CPN}	\overline{CAS} high pulse width	10		10		10		10		ns
t_{RAD}	Column address delay time from \overline{RAS} low (Note 15)	15	30	15	35	15	40	20	50	ns
t_{ASR}	Row address setup time before \overline{RAS} low	0		0		0		0		ns
t_{ASC}	Column address setup time before \overline{CAS} low (Note 16)	0	10	0	10	0	15	0	20	ns
t_{RAH}	Row address hold time after \overline{RAS} low	10		10		10		15		ns
t_{CAH}	Column address hold time after \overline{CAS} low	15		15		15		20		ns
t_T	Transition time (Note 17)	1	50	1	50	1	50	1	50	ns

- Note 12: The timing requirements are assumed $t_T = 5\text{ns}$.
 13: $V_{IH(min)}$ and $V_{IL(max)}$ are reference levels for measuring timing of input signals.
 14: $t_{RCD(max)}$ is specified as a reference point only. If t_{RCD} is less than $t_{RCD(max)}$, access time is t_{RAC} . If t_{RCD} is greater than $t_{RCD(max)}$, access time is controlled exclusively by t_{CAC} or t_{AA} . $t_{RCD(min)}$ is specified as $t_{RCD(min)} = t_{RAH(min)} + 2t_T + t_{ASC(min)}$.
 15: $t_{RAD(max)}$ is specified as a reference point only. If $t_{RAD} \geq t_{RAD(max)}$ and $t_{ASC} \leq t_{ASC(max)}$, access time is controlled exclusively by t_{AA} .
 16: $t_{ASC(max)}$ is specified as a reference point only. If $t_{RCD} \geq t_{RCD(max)}$ and $t_{ASC} \geq t_{ASC(max)}$, access time is controlled exclusively by t_{CAC} .
 17: t_T is measured between $V_{IH(min)}$ and $V_{IL(max)}$.

M5M44100AWJ,J,L,TP,RT-6,-7,-8,-10**FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT) DYNAMIC RAM****Read and Refresh Cycles**

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{RC}	Read cycle time	120		140		160		190		ns
t_{RAS}	\overline{RAS} low pulse width	60	10000	70	10000	80	10000	100	10000	ns
t_{CAS}	\overline{CAS} low pulse width	15	10000	20	10000	20	10000	25	10000	ns
t_{CSH}	\overline{CAS} hold time after \overline{RAS} low	60		70		80		100		ns
t_{RSH}	\overline{RAS} hold time after \overline{CAS} low	15		20		20		25		ns
t_{RCS}	Read setup time before \overline{CAS} low	0		0		0		0		ns
t_{RCH}	Read hold time after \overline{CAS} high (Note 18)	0		0		0		0		ns
t_{RRH}	Read hold time after \overline{RAS} high (Note 18)	10		10		10		10		ns
t_{RAL}	Column address to \overline{RAS} hold time	30		35		40		50		ns

Note 18: Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.

Write Cycle (Early Write and Delayed Write Cycles)

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{WC}	Write cycle time	120		140		160		190		ns
t_{RAS}	\overline{RAS} low pulse width	60	10000	70	10000	80	10000	100	10000	ns
t_{CAS}	\overline{CAS} low pulse width	15	10000	20	10000	20	10000	25	10000	ns
t_{CSH}	\overline{CAS} hold time after \overline{RAS} low	60		70		80		100		ns
t_{RSH}	\overline{RAS} hold time after \overline{CAS} low	15		20		20		25		ns
t_{WCS}	Write setup time before \overline{CAS} low (Note 21)	0		0		0		0		ns
t_{WCH}	Write hold time after \overline{CAS} low	10		15		15		20		ns
t_{CWL}	\overline{CAS} hold time after \overline{W} low	15		20		20		25		ns
t_{RWL}	\overline{RAS} hold time after \overline{W} low	15		20		20		25		ns
t_{WP}	Write pulse width	10		15		15		20		ns
t_{DS}	Data setup time before \overline{CAS} low or \overline{W} low	0		0		0		0		ns
t_{DH}	Data hold time after \overline{CAS} low or \overline{W} low	10		15		15		20		ns

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Read-Write and Read-Modify-Write Cycles

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{RWC}	Read write cycle time (Note 19)	140		165		185		220		ns
t _{RMWC}	Read modify write cycle time (Note 20)	140		165		185		220		ns
t _{RAS}	$\overline{\text{RAS}}$ low pulse width	85	10000	95	10000	105	10000	130	10000	ns
t _{CAS}	$\overline{\text{CAS}}$ low pulse width	40	10000	45	10000	45	10000	55	10000	ns
t _{CSH}	$\overline{\text{CAS}}$ hold time after $\overline{\text{RAS}}$ low	85		95		105		130		ns
t _{RSH}	$\overline{\text{RAS}}$ hold time after $\overline{\text{CAS}}$ low	40		45		45		55		ns
t _{RCS}	Read setup time before $\overline{\text{CAS}}$ low	0		0		0		0		ns
t _{CWD}	Delay time, $\overline{\text{CAS}}$ low to $\overline{\text{W}}$ low (Note 21)	15		20		20		25		ns
t _{RWD}	Delay time, $\overline{\text{RAS}}$ low to $\overline{\text{W}}$ low (Note 21)	60		70		80		100		ns
t _{AWD}	Delay time, address to $\overline{\text{W}}$ low (Note 21)	30		35		40		50		ns
t _{CWL}	$\overline{\text{CAS}}$ hold time after $\overline{\text{W}}$ low	15		20		20		25		ns
t _{RWL}	$\overline{\text{RAS}}$ hold time after $\overline{\text{W}}$ low	15		20		20		25		ns
t _{WP}	Write pulse width	10		15		15		20		ns
t _{DS}	Data setup time before $\overline{\text{W}}$ low	0		0		0		0		ns
t _{DH}	Data hold time after $\overline{\text{W}}$ low	10		15		15		20		ns

Note 19: t_{RWC} is specified as t_{RWC(min)} = t_{RCD(max)} + t_{CWD(min)} + t_{RWL(min)} + t_{RP(min)} + 3t_T.

Note 20: t_{RMWC} is specified as t_{RMWC(min)} = t_{RAC(max)} + t_{RWL(min)} + t_{RP(min)} + 3t_T.

Note 21: t_{WCS}, t_{RWD}, t_{CWD}, t_{AWD} and t_{CPWD} do not define the limits of operation, but are included as electrical characteristics only.

When t_{WCS} ≥ t_{WCS(min)}, an early-write cycle is performed, and the data output keeps the high-impedance state. When t_{RWD} ≥ t_{RWD(min)}, t_{AWD} ≥ t_{AWD(min)} and t_{CPWD} ≥ t_{CPWD(min)} (for fast page mode cycle only), a read-write cycle is performed, and the data of the selected address will be read out on the data output. If neither of the above condition (delayed write) is satisfied, the condition of Q (at access time and until $\overline{\text{CAS}}$ goes back to V_{IH}) is indeterminate.

Fast Page Mode Cycle (Read, Write, Read-Write and Read-Modify-Write Cycles) (Note 22)

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{PC}	Fast page mode read/write cycle time	40		45		50		60		ns
t _{PRWC}	Fast page mode read write/read modify write cycle time	60		70		75		90		ns
t _{RAS}	$\overline{\text{RAS}}$ low pulse width for read write cycle (Note 23)	105	200000	115	200000	130	200000	160	200000	ns
t _{CP}	$\overline{\text{CAS}}$ high pulse width (Note 24)	10	15	10	20	10	20	10	25	ns
t _{CPPH}	$\overline{\text{RAS}}$ hold time after $\overline{\text{CAS}}$ precharge	35		40		45		55		ns
t _{CPWD}	Delay time, $\overline{\text{CAS}}$ precharge to $\overline{\text{W}}$ low (Note 21)	35		40		45		55		ns

Note 22: All previously specified timing requirements and switching characteristics are applicable to their respective fast page mode cycle.

Note 23: t_{RAS(min)} is specified as two cycles of $\overline{\text{CAS}}$ input are performed.

Note 24: t_{CP(max)} is specified as a reference point only.

$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh Cycle (Note 25)

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{CSR}	$\overline{\text{CAS}}$ setup time before $\overline{\text{RAS}}$ low	10		10		10		10		ns
t _{CHR}	$\overline{\text{CAS}}$ hold time after $\overline{\text{RAS}}$ low	10		15		15		20		ns
t _{RSR}	Read setup time before $\overline{\text{RAS}}$ low	10		10		10		10		ns
t _{RHR}	Read hold time after $\overline{\text{RAS}}$ low	10		15		15		20		ns
t _{CAS}	$\overline{\text{CAS}}$ low pulse width	25		30		30		35		ns

Note 25: Eight or more $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ cycles instead of eight $\overline{\text{RAS}}$ cycles are necessary for proper operation of $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh mode.

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TEST MODE SPECIFICATION (Note 26)

ELECTRICAL CHARACTERISTICS (Ta=0-70°C, VCC=5V±10%, VSS=0V, unless otherwise noted) (Note 2)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
I _{CC1(AV)}	Average supply current from V _{CC} operating (Note 3, 4)	$\overline{\text{RAS}}$, $\overline{\text{CAS}}$ cycling t _{RC} =t _{WC} =min. output open			115	mA
					100	
					85	
					75	
I _{CC3(AV)}	Average supply current from V _{CC} refreshing (Note 3)	$\overline{\text{RAS}}$ cycling, $\overline{\text{CAS}}=V_{IH}$ t _{RC} =min output open			115	mA
					100	
					85	
					75	
I _{CC4(AV)}	Average supply current from V _{CC} Fast-Page-Mode (Note 3, 4)	$\overline{\text{RAS}}=V_{IL}$, $\overline{\text{CAS}}$ cycling t _{PC} =min. output open			115	mA
					100	
					85	
					75	
I _{CC6(AV)}	Average supply current from V _{CC} $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh mode (Note 3)	$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh cycling t _{RC} =min. output open			100	mA
					85	
					75	
					65	

Note 26: All previously specified electrical characteristics, switching characteristics and timing requirements are applicable to that of test mode.

SWITCHING CHARACTERISTICS (Ta=0-70°C, VCC=5V±10%, VSS=0V, unless otherwise noted) (Notes 5, 12, 13)

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{CAC}	Access time from $\overline{\text{CAS}}$ (Note 6, 7)		20		25		25		30	ns
t _{RAC}	Access time from $\overline{\text{RAS}}$ (Note 6, 8)		65		75		85		105	ns
t _{AA}	Column address access time (Note 6, 9)		35		40		45		55	ns
t _{CPA}	Access time from $\overline{\text{CAS}}$ precharge (Note 6, 10)		40		45		50		60	ns

TIMING REQUIREMENTS (Ta=0-70°C, VCC=5V±10%, VSS=0V, unless otherwise noted) (Notes 12, 13)

Read and Refresh Cycles

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{RC}	Read cycle time	125		145		165		195		ns
t _{RAS}	$\overline{\text{RAS}}$ low pulse width	65	10000	75	10000	85	10000	105	10000	ns
t _{CAS}	$\overline{\text{CAS}}$ low pulse width	20	10000	25	10000	25	10000	30	10000	ns
t _{CSH}	$\overline{\text{CAS}}$ hold time after $\overline{\text{RAS}}$ low	65		75		85		105		ns
t _{RSH}	$\overline{\text{RAS}}$ hold time after $\overline{\text{CAS}}$ low	20		25		25		30		ns
t _{RAL}	Column address to $\overline{\text{RAS}}$ hold time	35		40		45		55		ns

M5M44100AWJ,J,L,TP,RT-6,-7,-8,-10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT)DYNAMIC RAM

Read-Write and Read-Modify-Write Cycles

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{RWC}	Read write cycle time (Note 19)	145		170		190		225		ns
t_{RMWC}	Read modify write cycle time (Note 20)	145		170		190		225		ns
t_{RAS}	\overline{RAS} low pulse width	90	10000	100	10000	110	10000	135	10000	ns
t_{CAS}	\overline{CAS} low pulse width	45	10000	50	10000	50	10000	60	10000	ns
t_{CSH}	\overline{CAS} hold time after \overline{RAS} low	90		100		110		135		ns
t_{RSH}	\overline{RAS} hold time after \overline{CAS} low	45		50		50		60		ns
t_{CWD}	Delay time, \overline{CAS} low to \overline{W} low (Note 21)	20		25		25		30		ns
t_{RWD}	Delay time, \overline{RAS} low to \overline{W} low (Note 21)	65		75		85		105		ns
t_{AWD}	Delay time, address to \overline{W} low (Note 21)	35		40		45		55		ns

Fast-Page Mode Cycle (Read, Write, Read-Write, and Read-Modify-Write Cycles) (Note 22)

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{PC}	Fast page mode read/write cycle time	45		50		55		65		ns
t_{PRWC}	Fast page mode read write/read modify write cycle time	65		75		80		95		ns
t_{RAS}	\overline{RAS} low pulse width for read write cycle (Note 23)	115	200000	125	200000	140	200000	170	200000	ns
t_{OPRH}	\overline{RAS} hold time after \overline{CAS} precharge	40		45		50		60		ns
t_{OPWD}	Delay time, \overline{CAS} precharge to \overline{W} low (Note 21)	40		45		50		60		ns

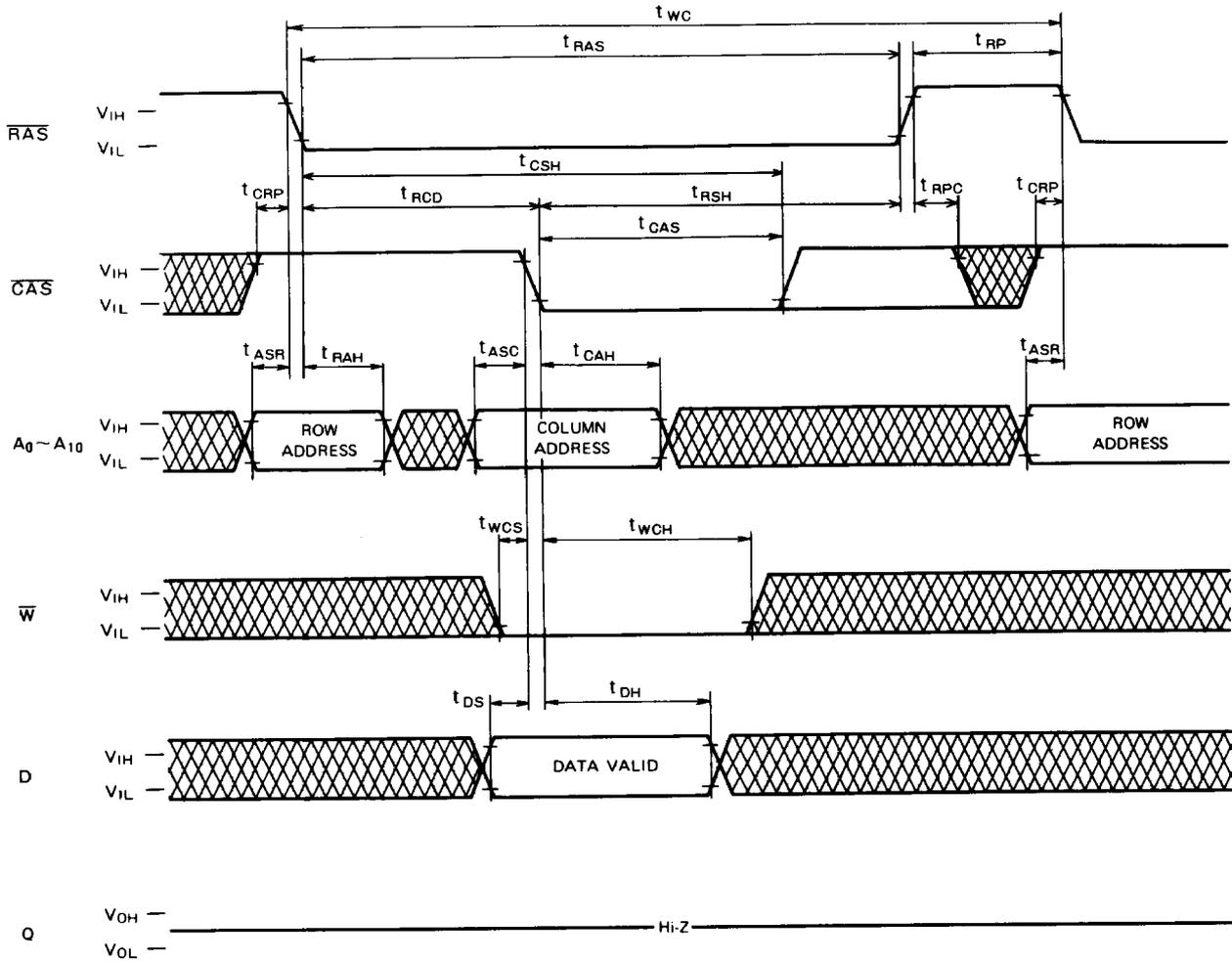
Test Mode Set Cycle

Symbol	Parameter	Limits								Unit
		M5M44100A-6		M5M44100A-7		M5M44100A-8		M5M44100A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{WSR}	Write setup time before \overline{RAS} low	10		10		10		10		ns
t_{WHR}	Write hold time after \overline{RAS} low	10		15		15		20		ns

M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT (4194304-WORD BY 1-BIT) DYNAMIC RAM

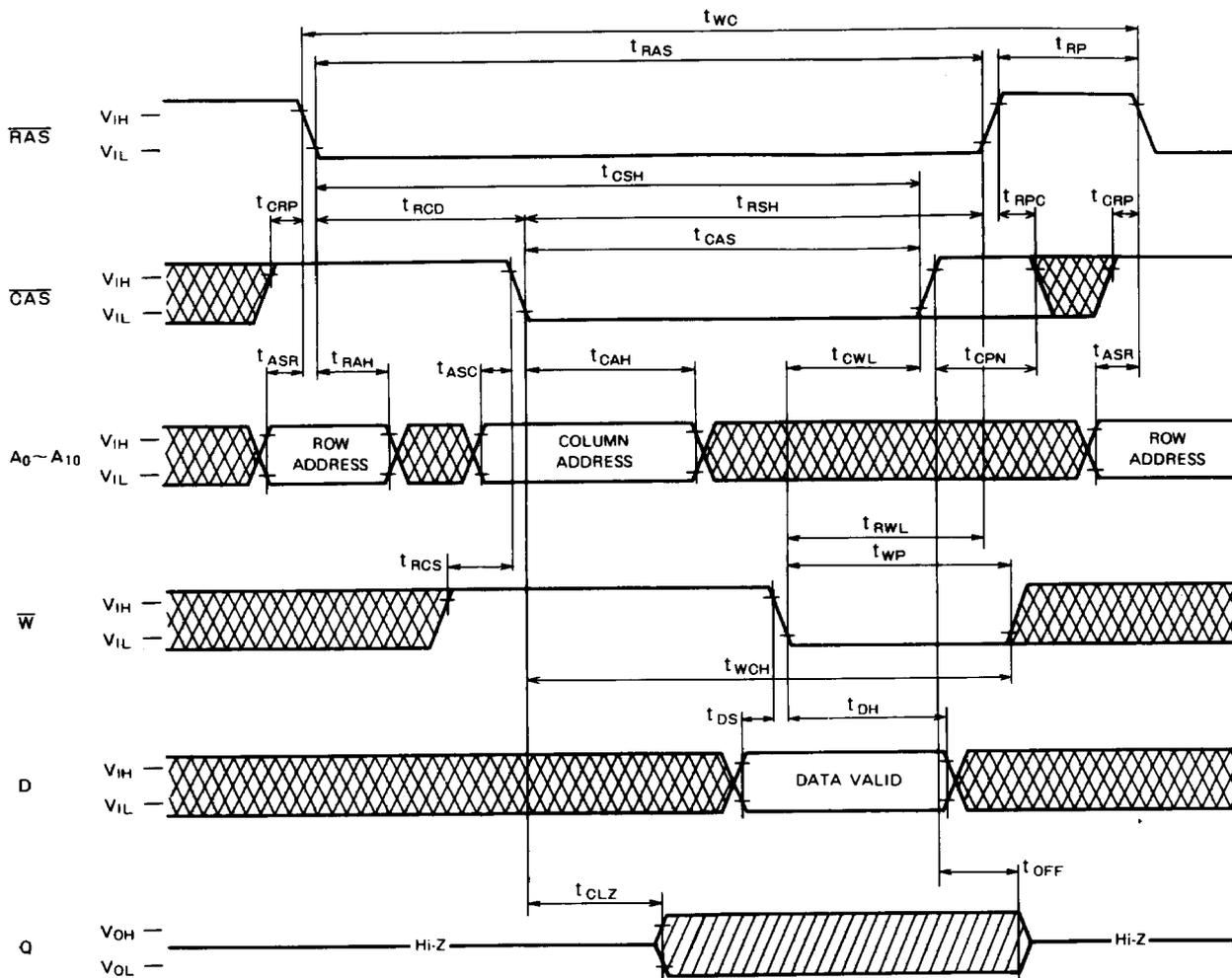
Write Cycle (Early Write)



M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT) DYNAMIC RAM

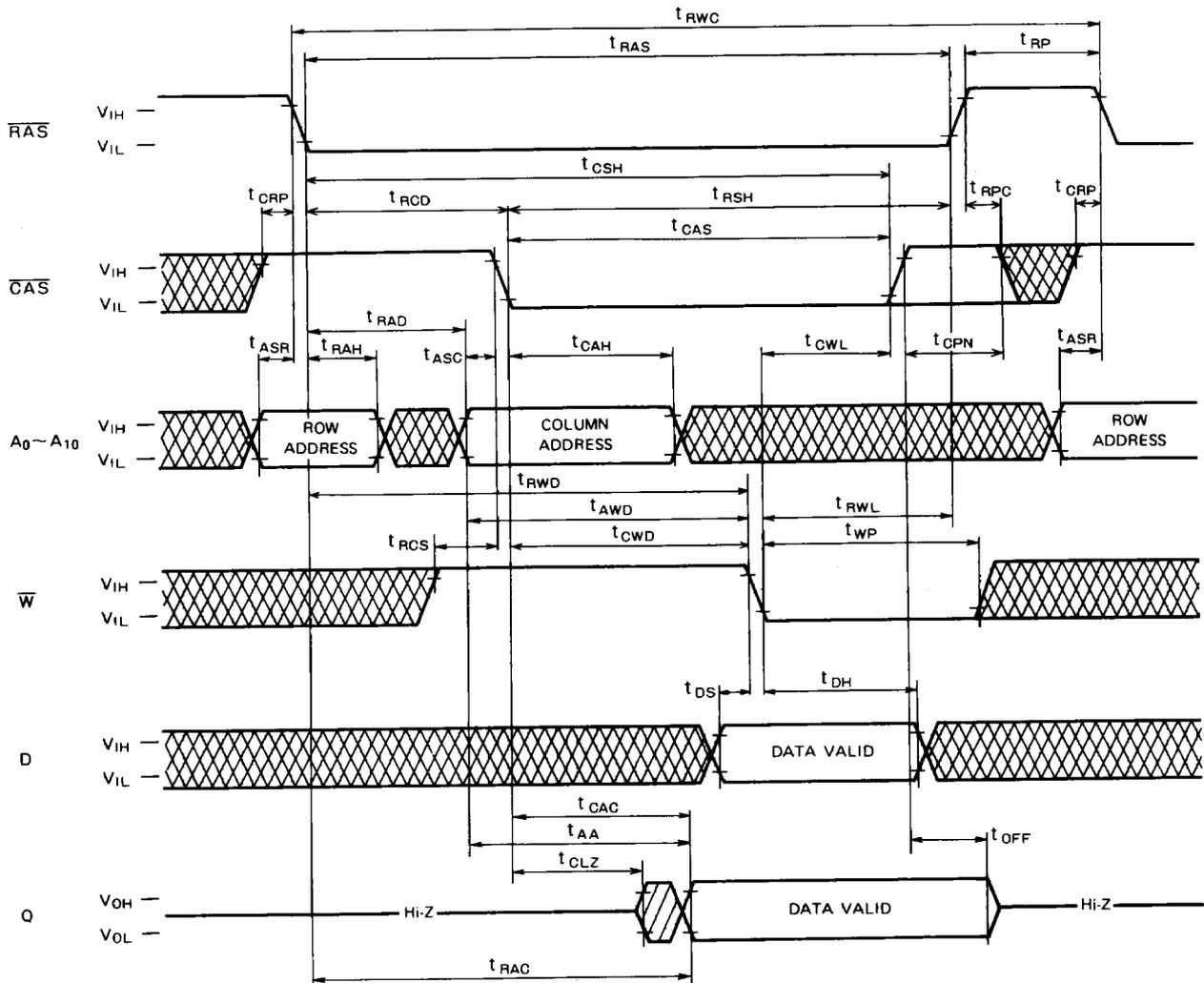
Write Cycle (Delayed Write)



M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT) DYNAMIC RAM

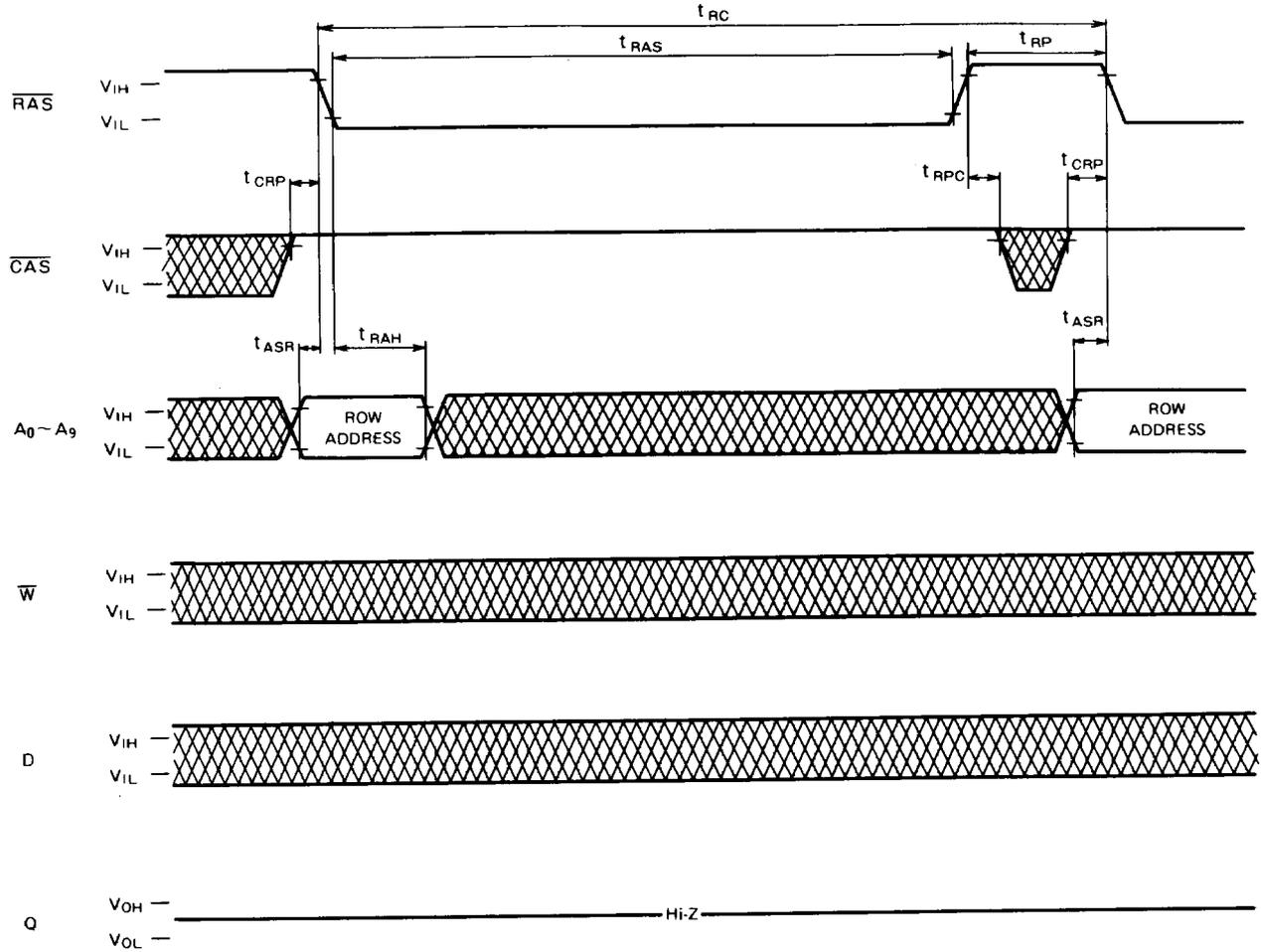
Read-Write, Read-Modify-Write Cycle



M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT) DYNAMIC RAM

RAS-only-Refresh Cycle (Note 28)

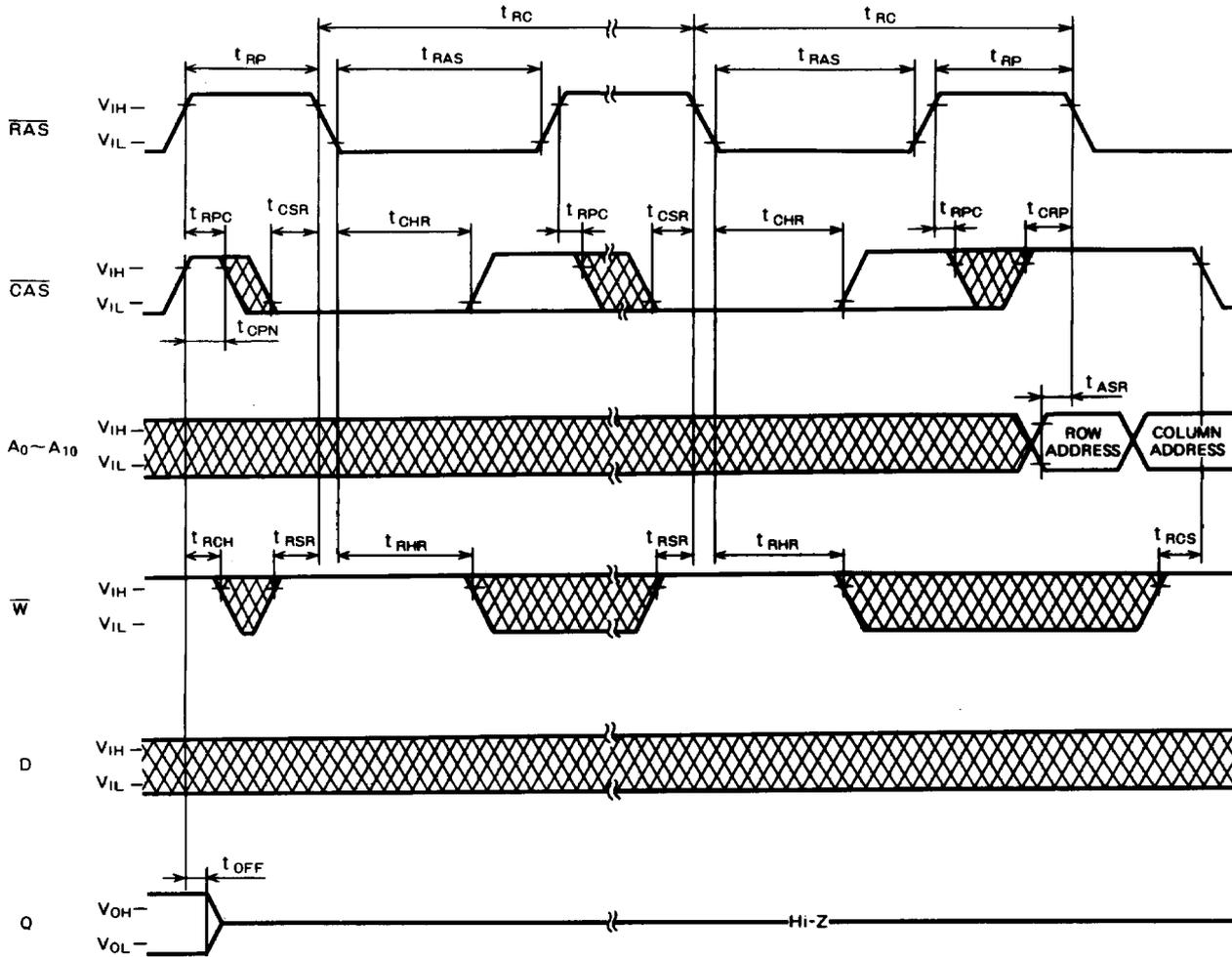


Note 28: A₁₀ may be V_{IH} or V_{IL} . Refresh address: A₀ (ROW)~A₉ (ROW).

M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT) DYNAMIC RAM

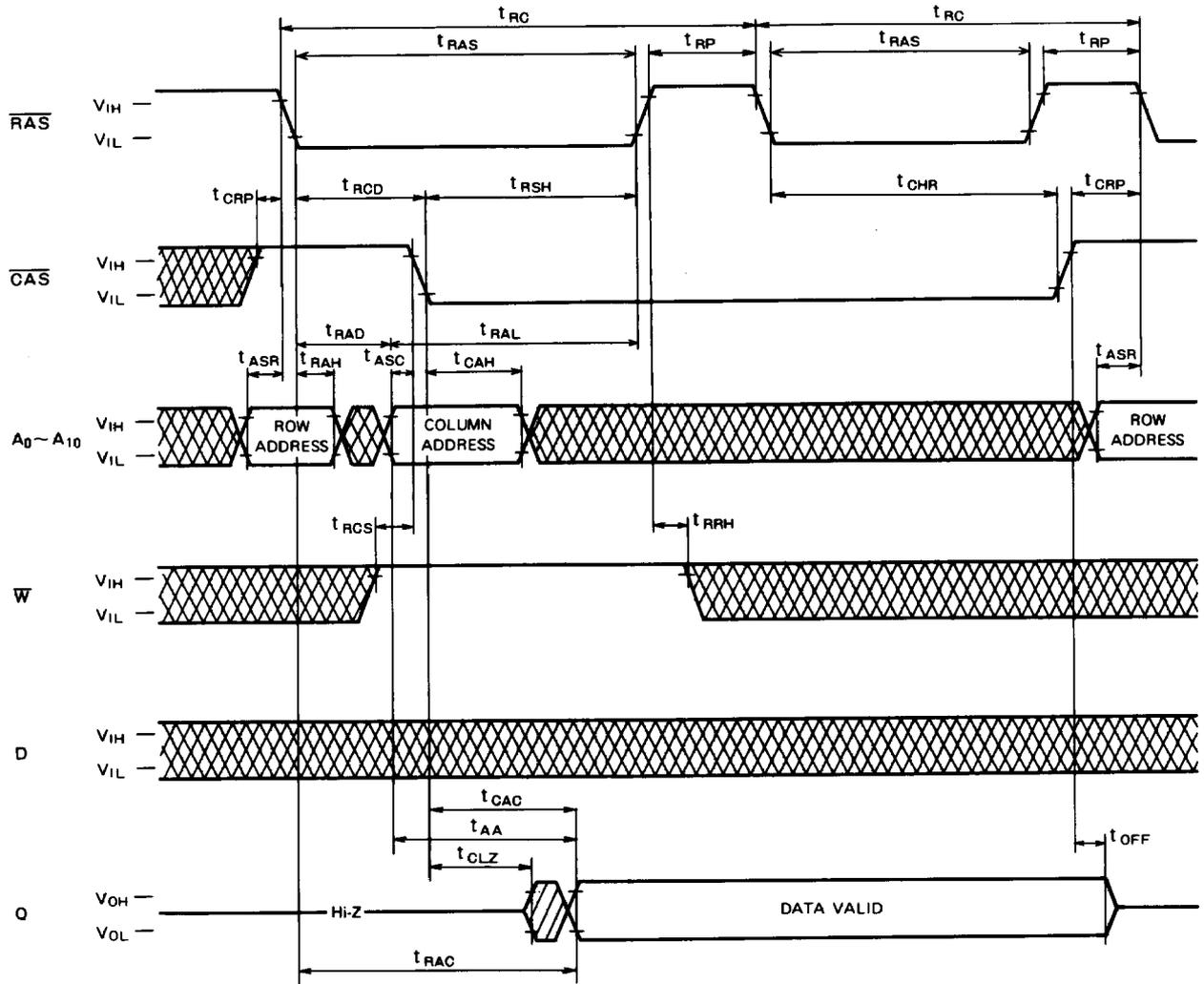
$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh Cycle



M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT (4194304-WORD BY 1-BIT) DYNAMIC RAM

Hidden Refresh Cycle (Read) (Note 29)

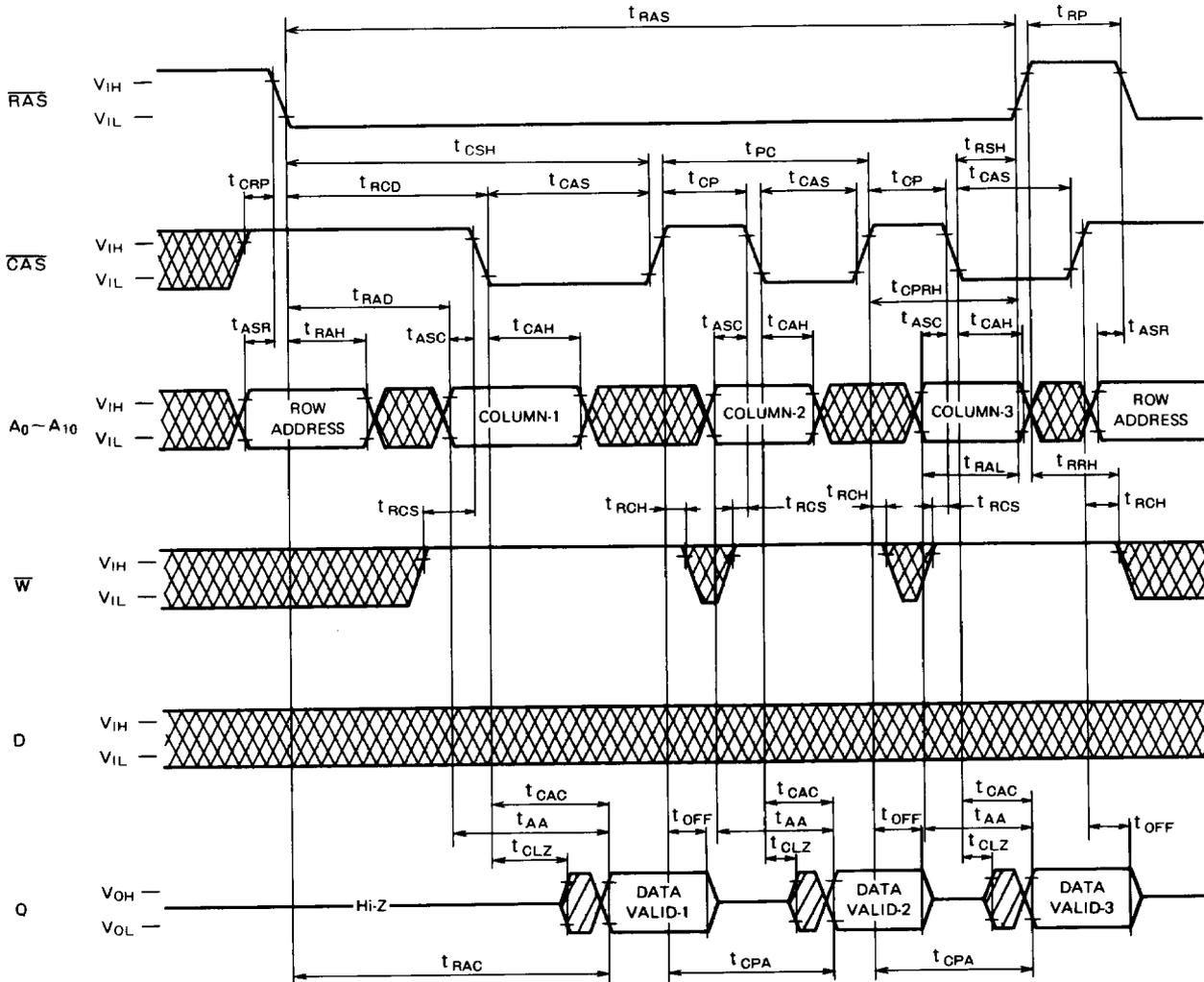


Note 29: Early write, delayed write, read write or read modify write cycle is applicable instead of read cycle. Timing requirements and output state are the same as that of each cycle shown above.

M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT (4194304-WORD BY 1-BIT) DYNAMIC RAM

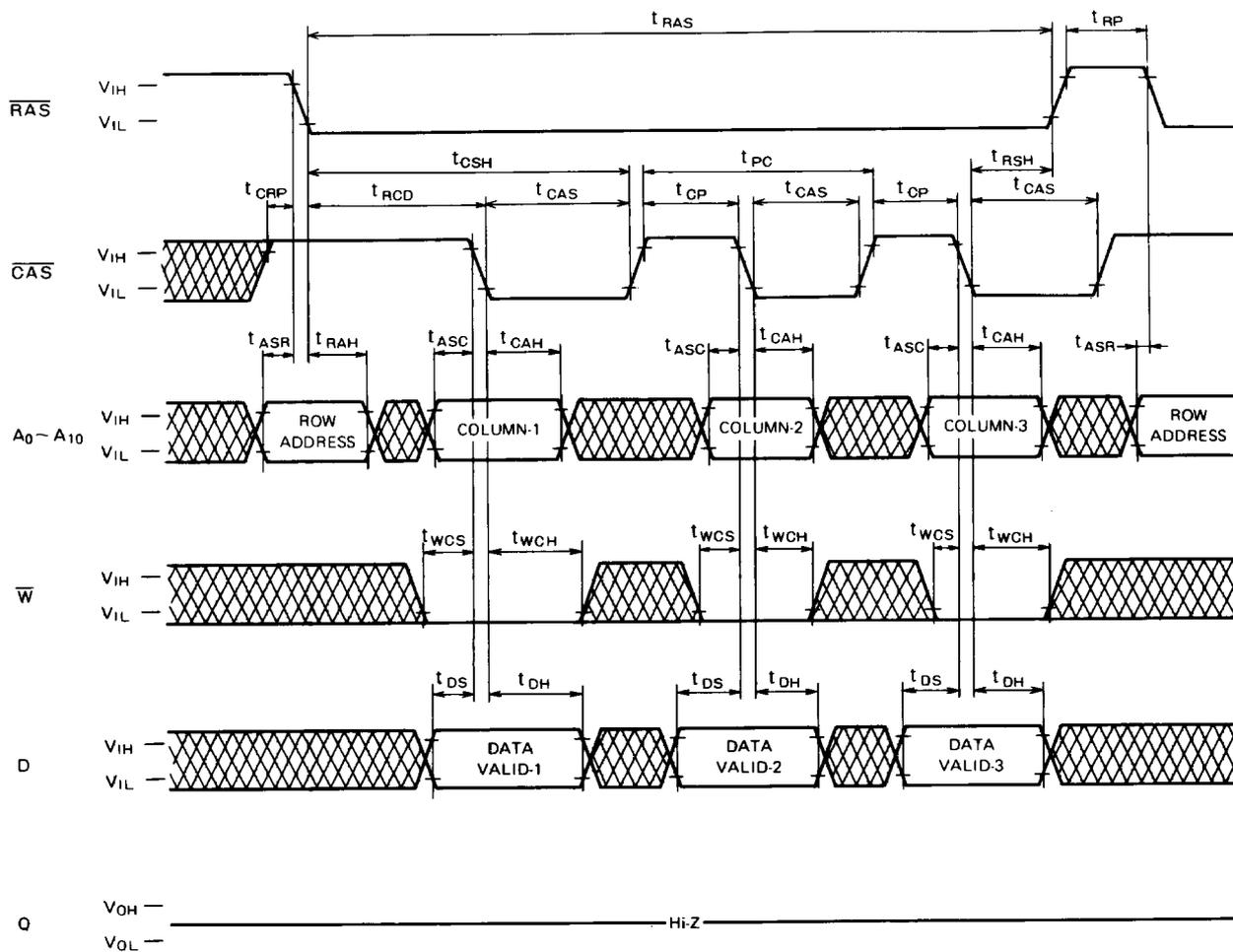
Fast-Page-Mode Read Cycle



M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT (4194304-WORD BY 1-BIT) DYNAMIC RAM

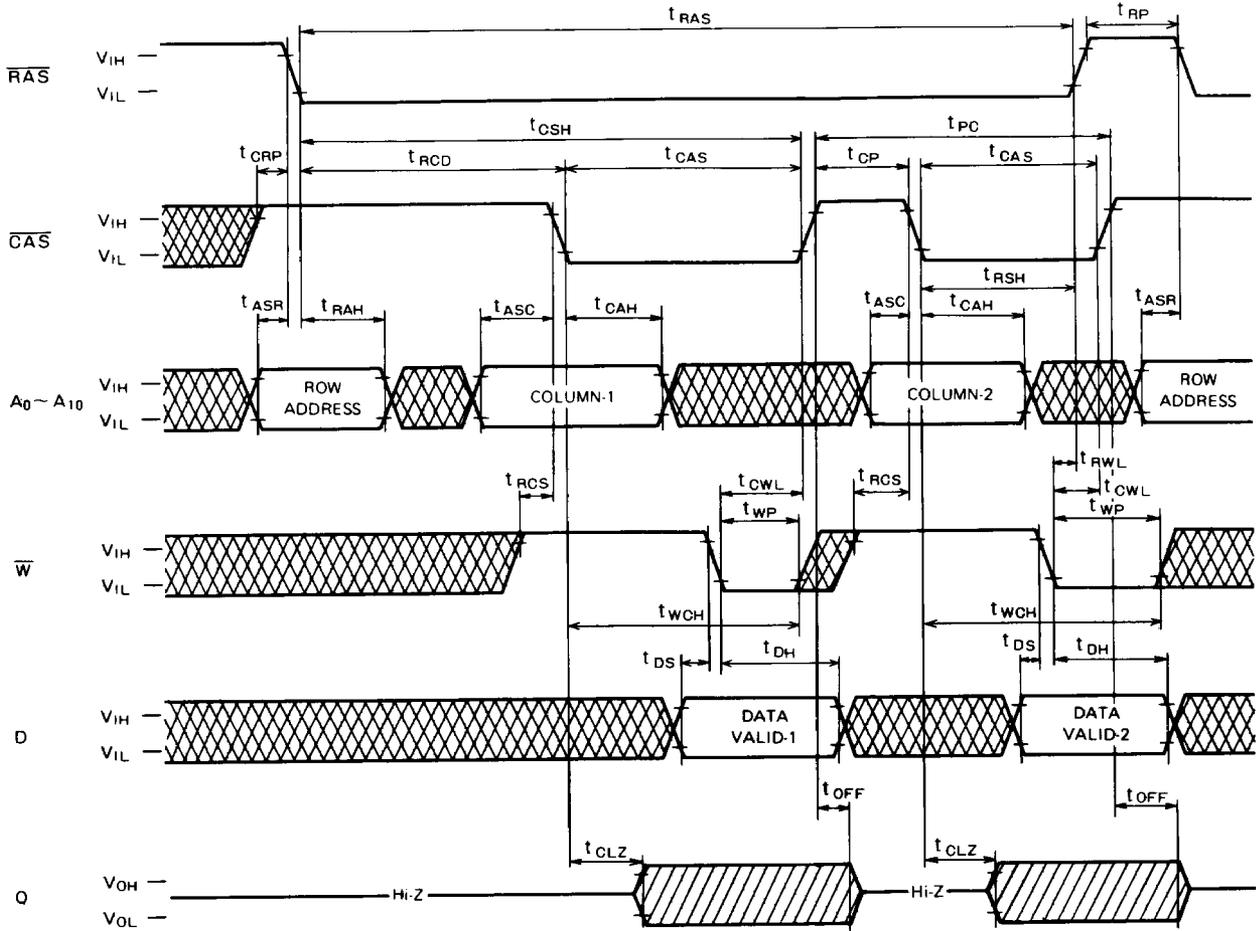
Fast-Page-Mode Write Cycle (Early Write)



M5M44100AWJ,J,L,TP,RT-6,-7,-8,-10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT) DYNAMIC RAM

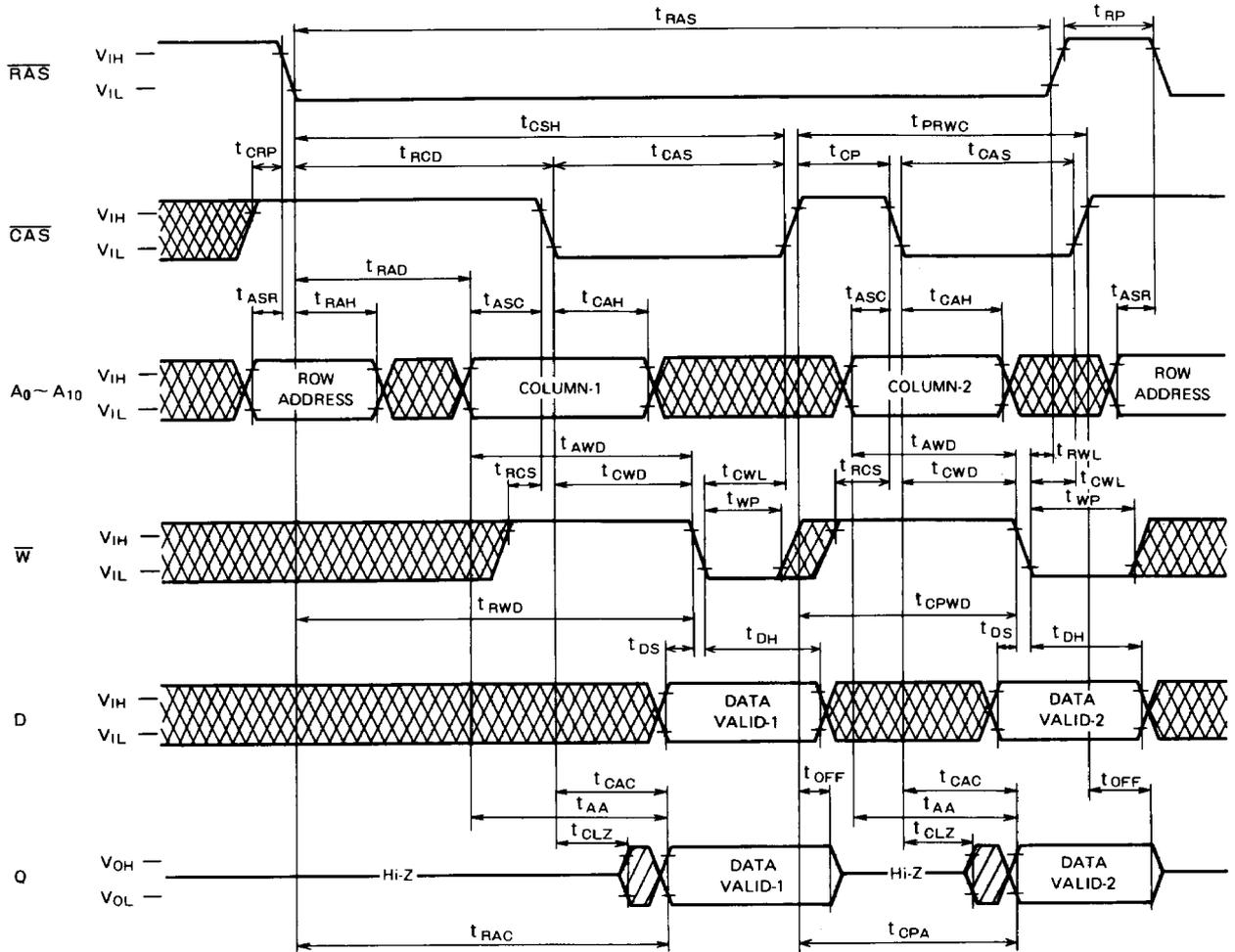
Fast-Page-Mode Write Cycle (Delayed Write)



M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT) DYNAMIC RAM

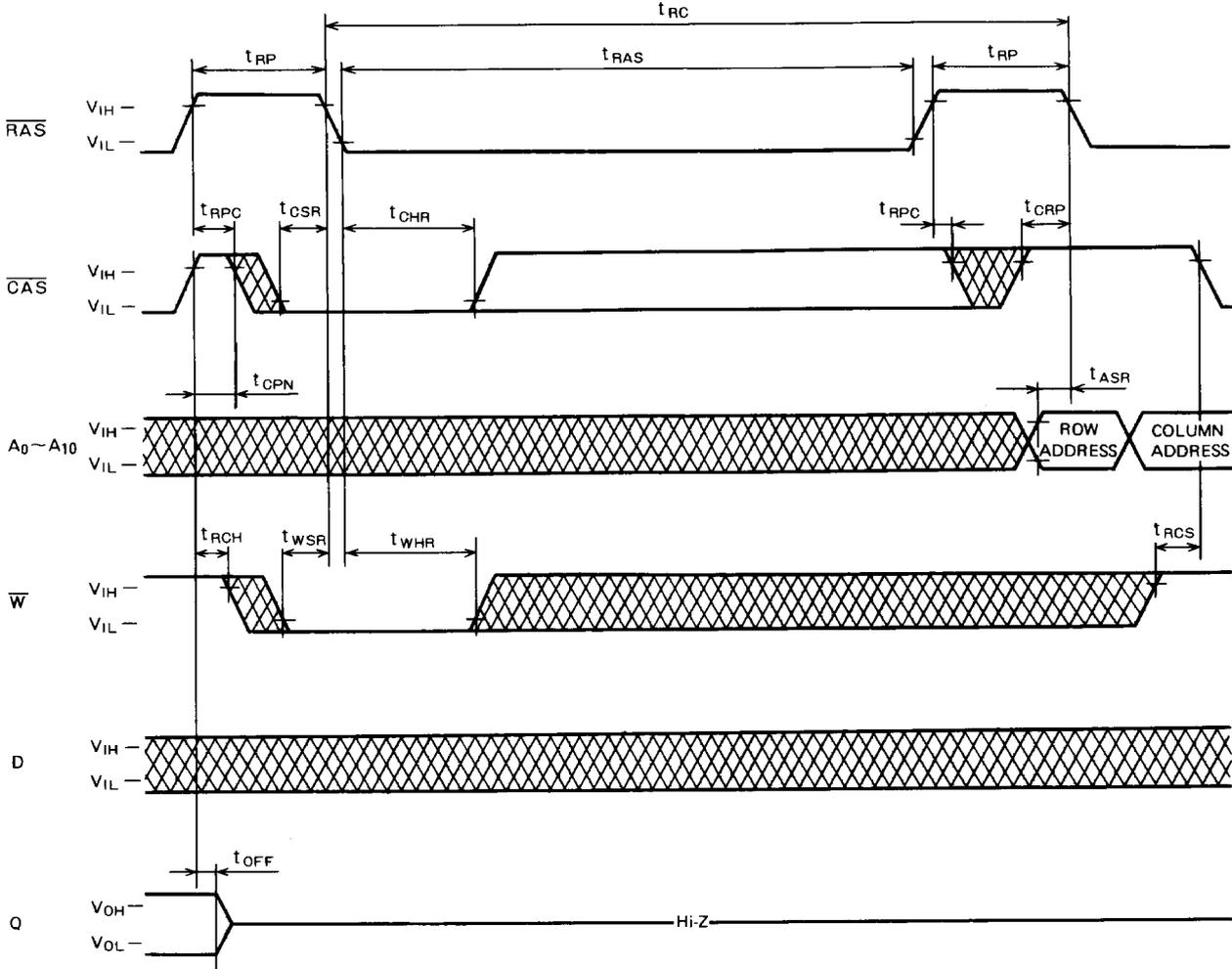
Fast-Page-Mode Read-Write, Read-Modify-Write Cycle



M5M44100AWJ,J,L,TP,RT-6,-7,-8,-10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT)DYNAMIC RAM

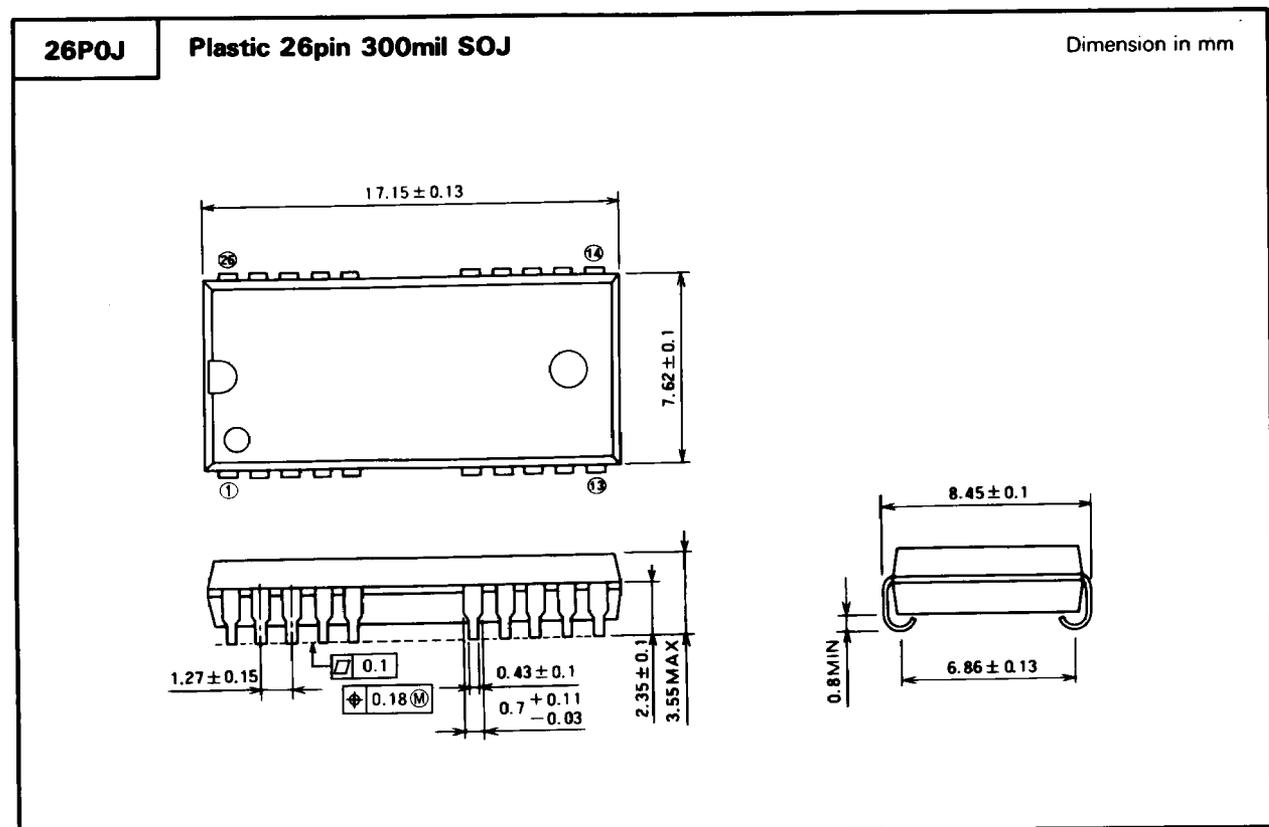
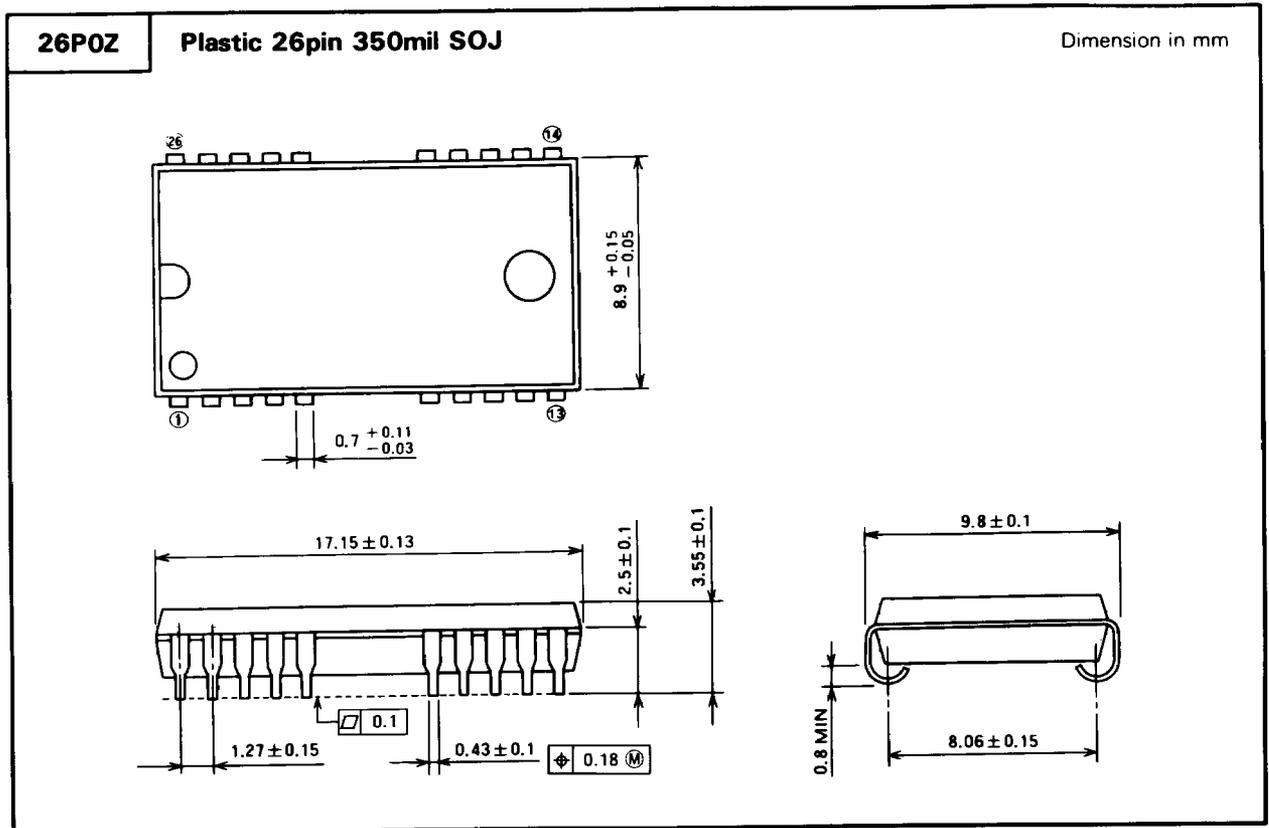
Test Mode Set Cycle (Note 30)



Note 30: This cycle is also available for the initialization cycle, but in this case device enters test mode. The test mode function is initiated with a \overline{W} and \overline{CAS} before \overline{RAS} cycle (WCBR cycle) as specified above timing diagram. The test mode function is terminated by either a \overline{CAS} before \overline{RAS} (CBR) refresh or a \overline{RAS} only refresh cycle. During the test mode, the device is internally organized as 16 bits wide (256 kilobytes deep). No addressing of A_{10} (both row and column) and A_0, A_1 (column only) is required. During a write cycle, data on the input pin is written in parallel into all 16 bits. During a read cycle, the output pin indicates a HIGH state if all 16 bits are equal, and a LOW state if any bits differ. During the test mode operation, a WCBR cycle is used to perform refresh.

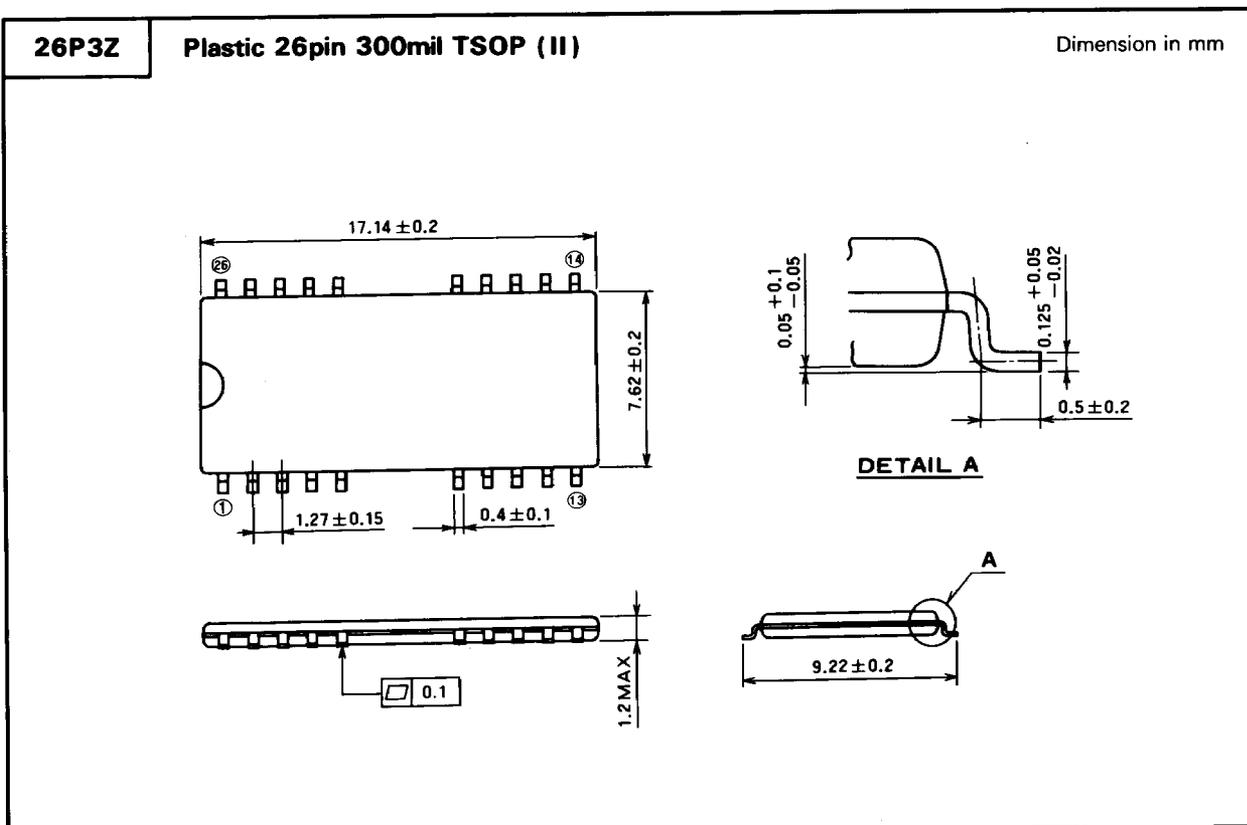
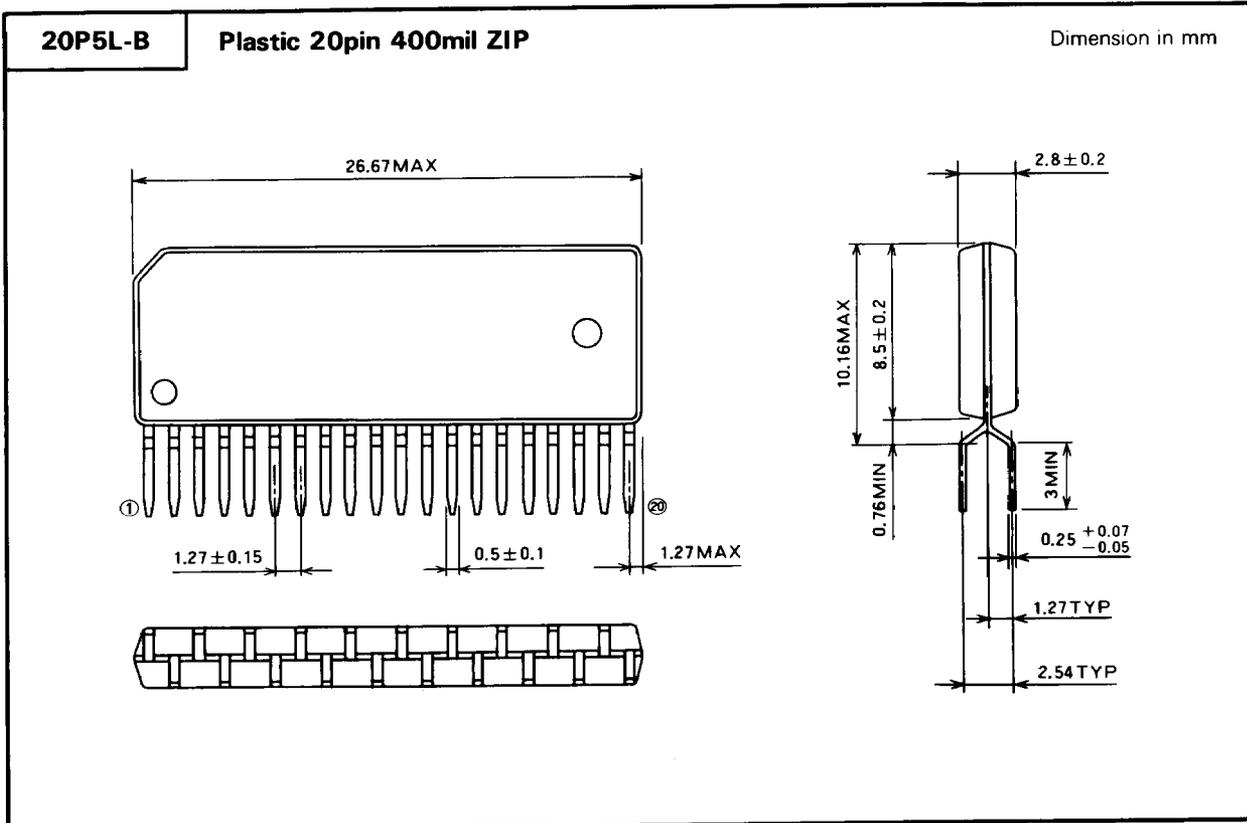
M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT)DYNAMIC RAM



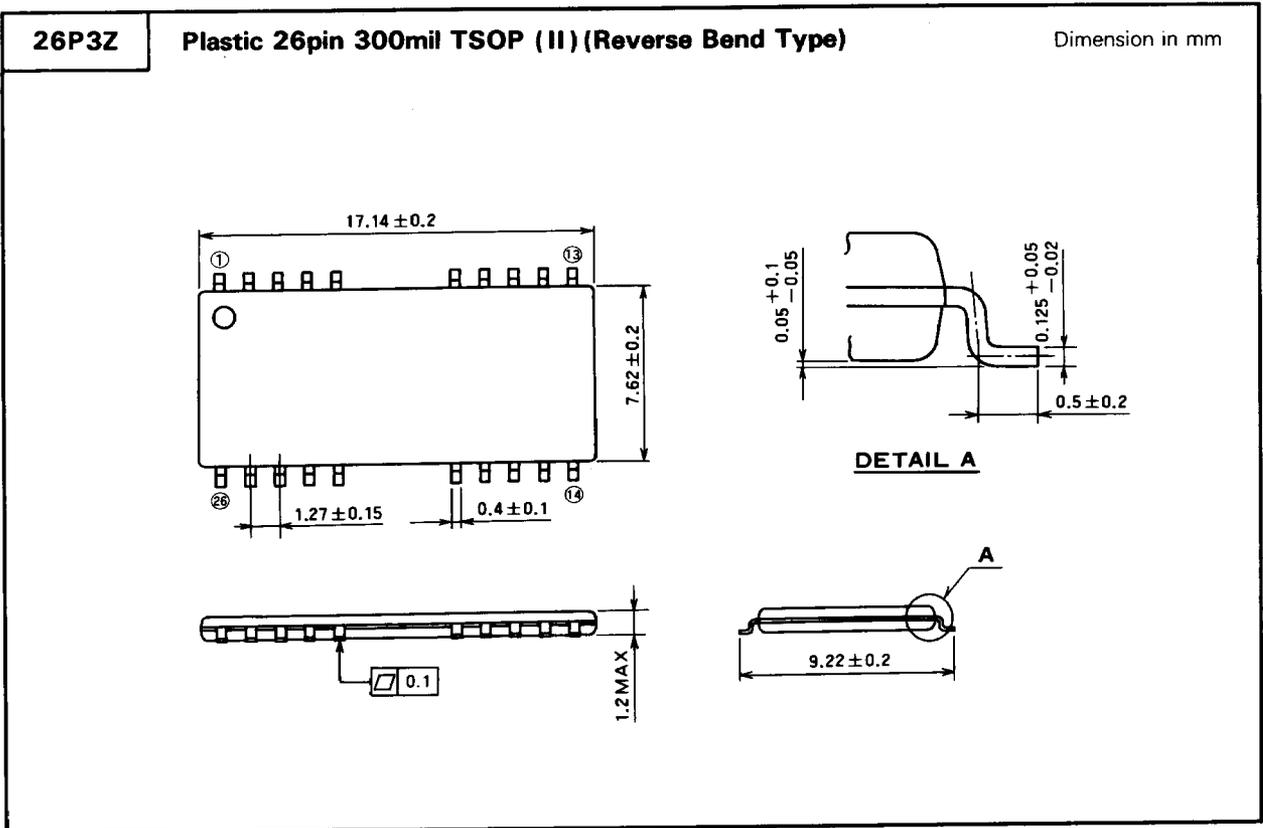
M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT)DYNAMIC RAM



M5M44100AWJ, J, L, TP, RT-6, -7, -8, -10

FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT)DYNAMIC RAM



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FAST PAGE MODE 4194304-BIT(4194304-WORD BY 1-BIT)DYNAMIC RAM

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